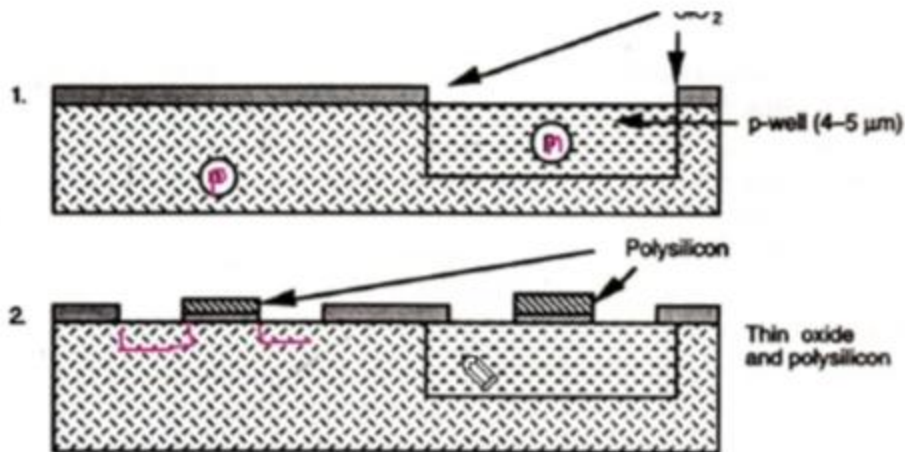
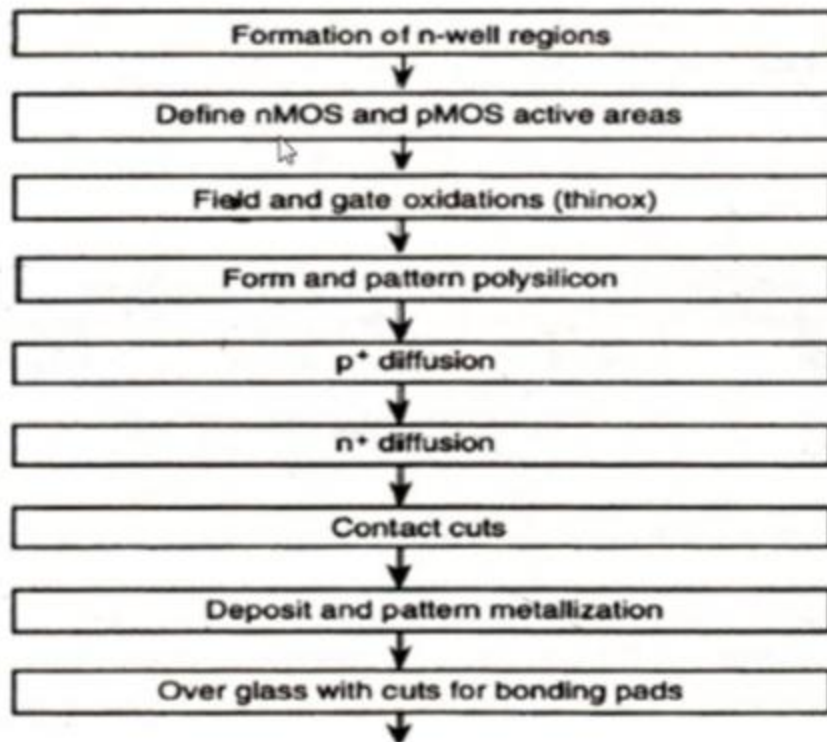


CMOS FABRICATION

- The p-well Process



The n-well Process



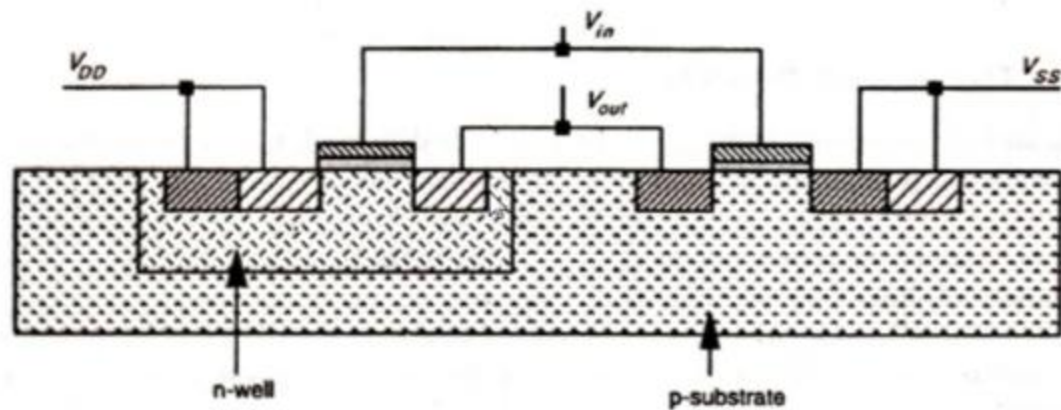


FIGURE 1.12 Cross-sectional view of n-well CMOS inverter.

The Twin-Tub Process

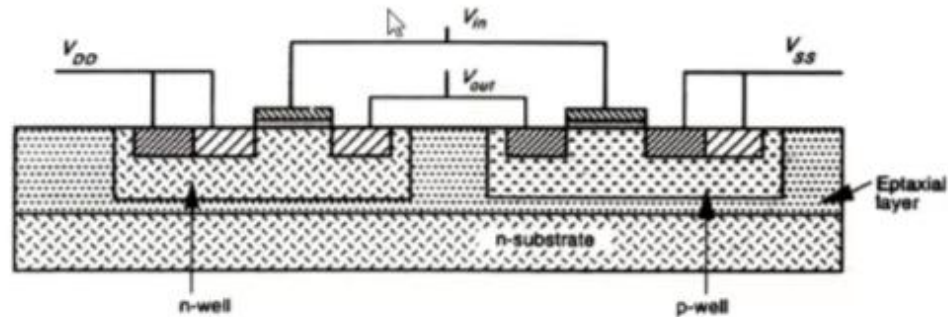
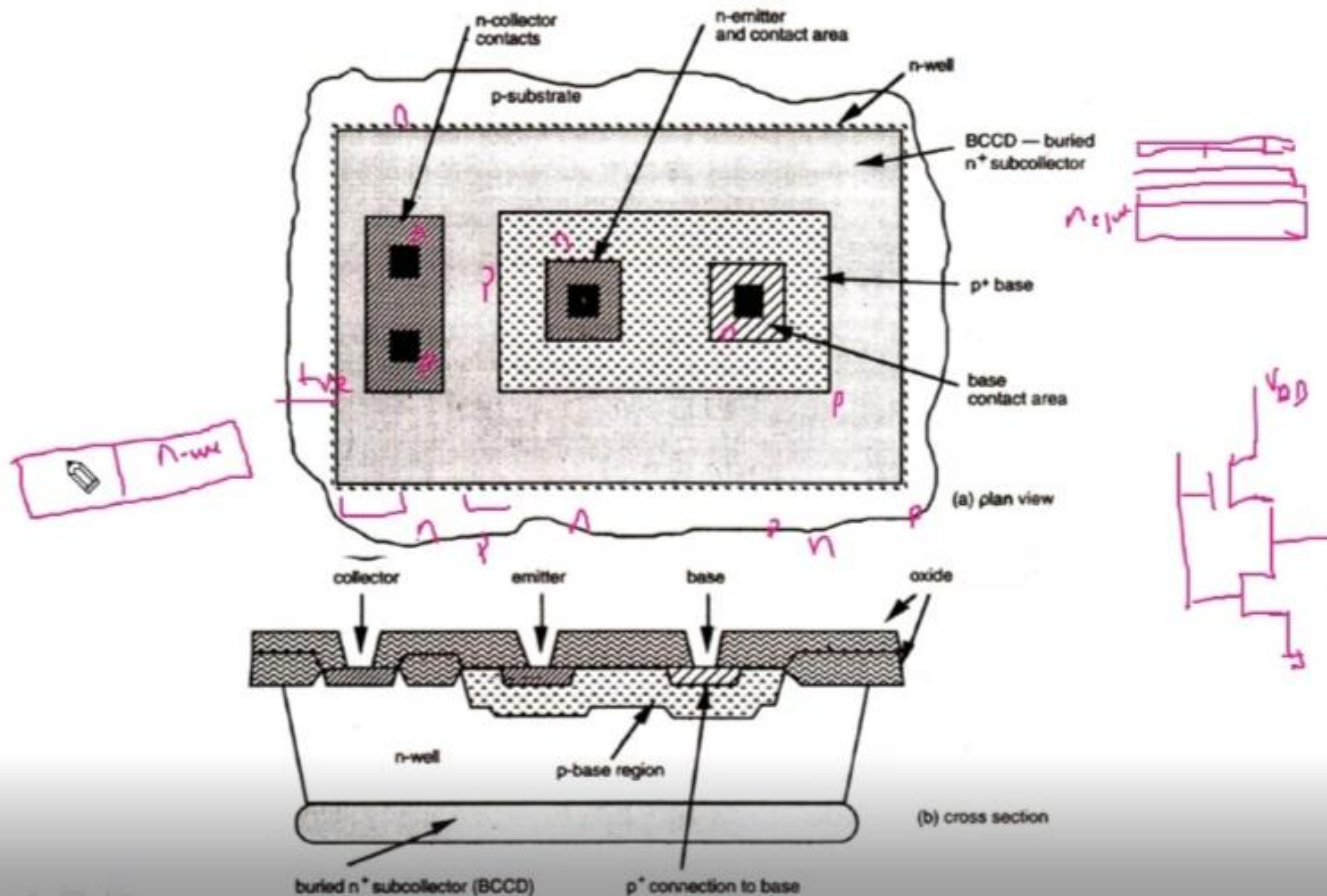


FIGURE 1.14 Twin-tub structure.

BICMOS TECHNOLOGY



Comparison of CMOS and Bipolar Technology

<i>CMOS technology</i>	<i>Bipolar technology</i>
<ul style="list-style-type: none">• Low static power dissipation• High input impedance (low drive current)• Scalable threshold voltage• High noise margin• High packing density• High delay sensitivity to load (fan-out limitations)• Low output drive current• Low g_m ($g_m \propto V_{in}$)• Bidirectional capability (drain and source are interchangeable)• A near ideal switching device	<ul style="list-style-type: none">• High power dissipation• Low input impedance (high drive current)• Low voltage swing logic• Low packing density• Low delay sensitivity to load• High output drive current• High g_m ($g_m \propto e^{V_{in}}$)• High f_t at low currents• Essentially unidirectional